

RefMat No


Category 1	Critical Dimensions
Category 2	Single Step
Category 3	Lateral (X-Y-axis, 1-dim)
Category 4	
Category 5	

 Type_of_RefMat:
Name of RM: Surface Topography References (STR)

Description Surface Topography References (STR)
combination of step height and pitch to enable three-dimensional calibration of optical interferometric microscopes and AFMs.

Link <http://www.vlsistandards.com/products/dimensional/streferences.asp?sid=31>

Certified Quantities

step height	MeanValue	18	nm	Uncertainty	<input type="text"/>	<input type="text"/>
step height	MeanValue	44	nm	Uncertainty	<input type="text"/>	<input type="text"/>
lateral distance	MeanValue	100	nm	Uncertainty	<input type="text"/>	<input type="text"/>
lateral distance	MeanValue	180	nm	Uncertainty	<input type="text"/>	<input type="text"/>
	MeanValue		nm	Uncertainty	<input type="text"/>	<input type="text"/>

Calibration of	AFM
Calibration of	SEM
Calibration of	Interferometer
Calibration of	WLIM
Calibration of	

Characterised by	<input type="text"/>
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Characterised by	<input type="text"/>
Characterised by	<input type="text"/>
Characterised by	<input type="text"/>

2 Provider
Provider No

Provider No	<input type="text" value="3"/>	Web address	<input type="text" value="http://www.vlsistandards.com"/>
Provider	VLSI Standards, Inc.		
Contact Person	<input type="text" value="Marc Helvey, ext. 108"/>	Country	<input type="text" value="USA"/>
Email	<input type="text" value="sales.support@vlsistd.com"/>	City	<input type="text" value="San Jose"/>
Phone	<input type="text" value="(408) 428-1800"/>	City Code	<input type="text" value="CA 95134-2006"/>
		Street + No	<input type="text" value="3087 North First Street"/>